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Rapid assessment of corn seed viability using short wave infrared line-scan hyperspectral imaging and chemometrics

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Highlights

- SWIR-HSI technology was used for measurement of corn seed viability.
- Three classification models (LDA, PLS-DA and SVM) were tested.
- The SVM model showed highest classification and image accuracy.
- The remarkable accuracy achieved demonstrated the potential of HSI for viability detection.
- This study is a major step towards development of a non-destructive large-scale HSI-based sorting system for corn viability measurement.

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